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**CONFIRMATION NO. 3511** 

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SERIAL NUMBER 10/783,087	FILING DATE 02/23/2004 RULE	CLASS 250	GROUP ART 2881		ATTORNEY DOCKET NO. 31468-0308336	
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** CONTINUING DATA **********************************						
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IF REQUIRED, FORE ** 05/13/2004	IGN FILING LICENSE	GRANTED				
Foreign Priority claimed 35 USC 119 (a-d) conditions	yes no no Met afte	STATE OR	SHEETS	TOTAL	INDEPENDENT	
met Verified and Acknowledged	Allowance  Allowance  Miner's Signature  Allowance  Init	COUNTRY NETHERLAND	DRAWING 6	CLAIMS 31	CLAIMS 5	
ADDRESS 00909 PILLSBURY WINTHR P.O. BOX 10500 MCLEAN , VA 22102	OP, LLP					
TITLE  Method and device for measuring contamination of a surface of a component of a lithographic apparatus						
			☐ All F	ees		

FILING FEE	FEES: Authority has been given in Paper	1.16 Fees (Filing)  1.17 Fees (Processing Ext. of time)
RECEIVED	No to charge/credit DEPOSIT ACCOUNT No. for following:	☐ 1.18 Fees (Issue)
1270		Other
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